

PRIFYSGOL AERDY

Polariton dynamics in planar microcavities: The effect of cross-hatch disorder

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sample in helium cryostat at 10K

• spot size ~1mm

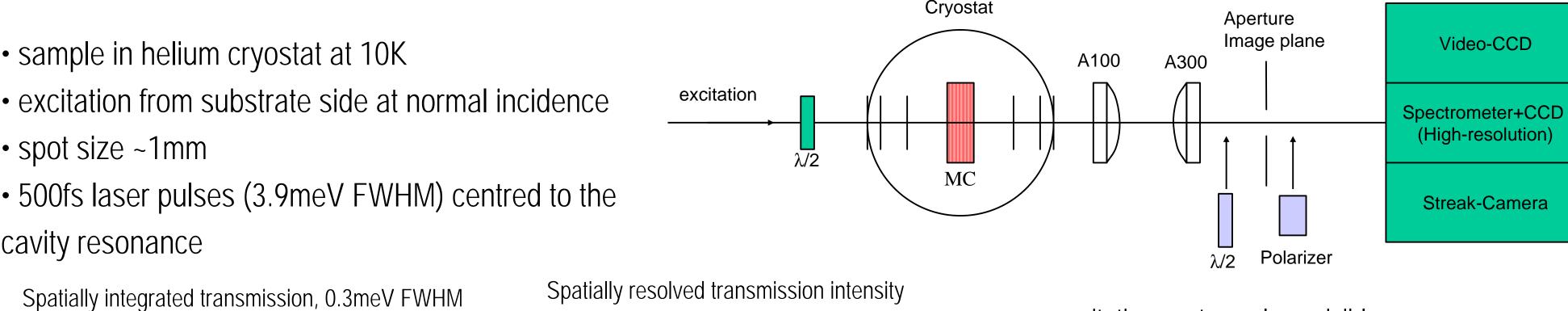
cavity resonance

Introduction

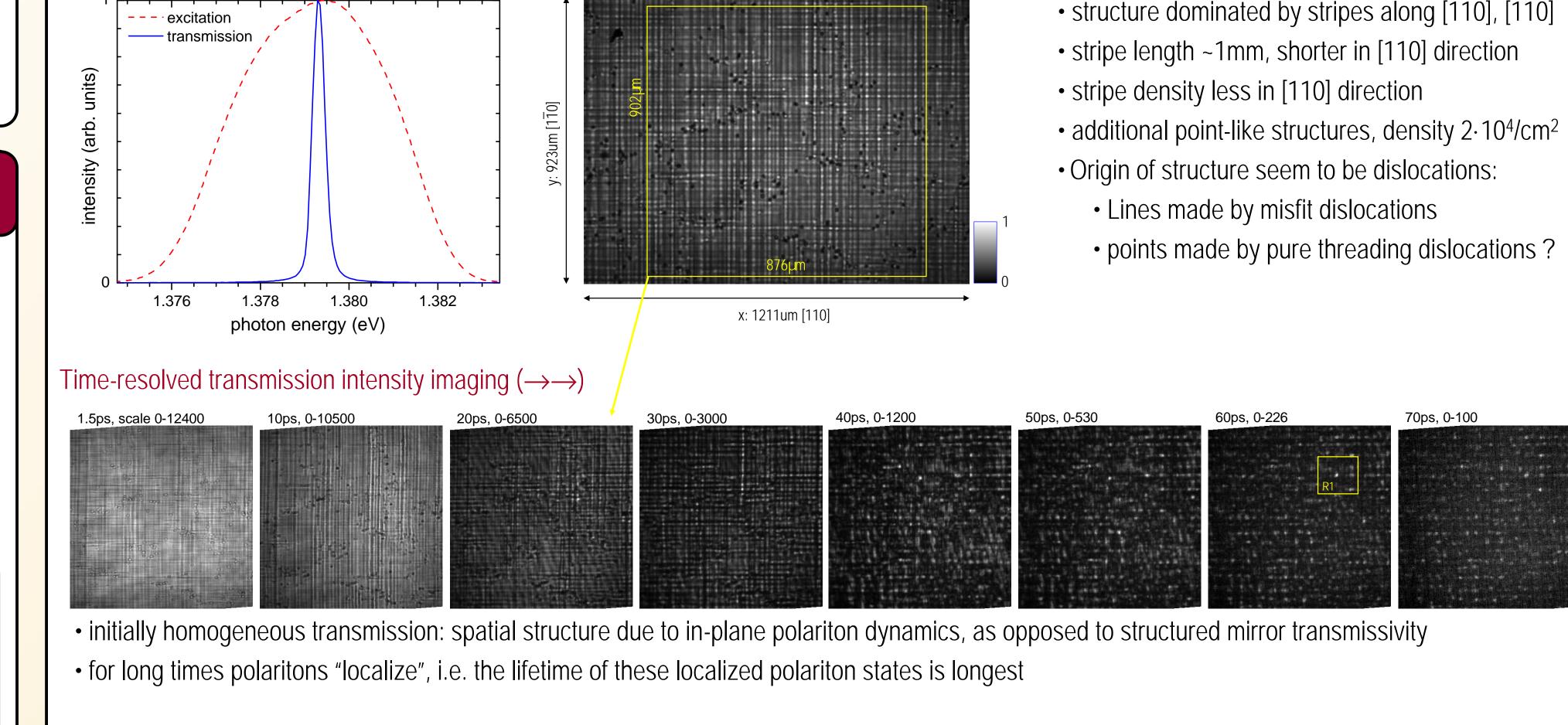
Planar semiconductor microcavities create a confined light mode in one direction by Bragg reflectors, while the in-plane motion of the light is free in ideal structures. The Bragg reflectors can be designed to a reflection coefficient arbitrarily close to unity, in which case the properties of the light modes are dominated by in-plane disorder, which determines the cavity linewidth measured, both for the inhomogeneous broadening and the homogeneous broadening of the modes

We have investigated this in-plane disorder on an empty microcavity of a high Bragg reflectivity, and identify the cross-hatch dislocation pattern formed due to the lattice mismatch as main disorder

Experiment: Time & spectrally resolved transmission imaging



Excitation & detection polarization along $x (\rightarrow \rightarrow)$

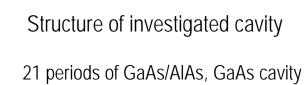


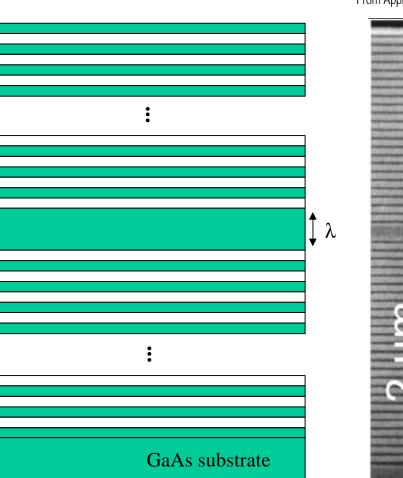
 excitation spot envelope visible • structure dominated by stripes along [110], [110]



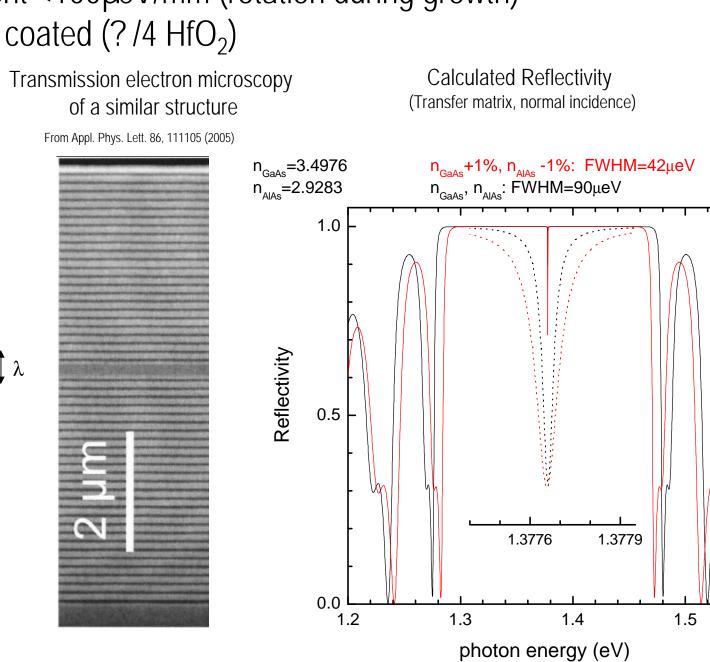
Microcavity structure

- grown by molecular beam epitaxy (MBE)
- 21 period GaAs/AIAs Bragg mirrors
- 1 ? GaAs cavity
- resonant wavelength 900nm at low temperatures • negligible cavity gradient <100µeV/mm (rotation during growth) • backside antireflection coated (? /4 HfO₂)



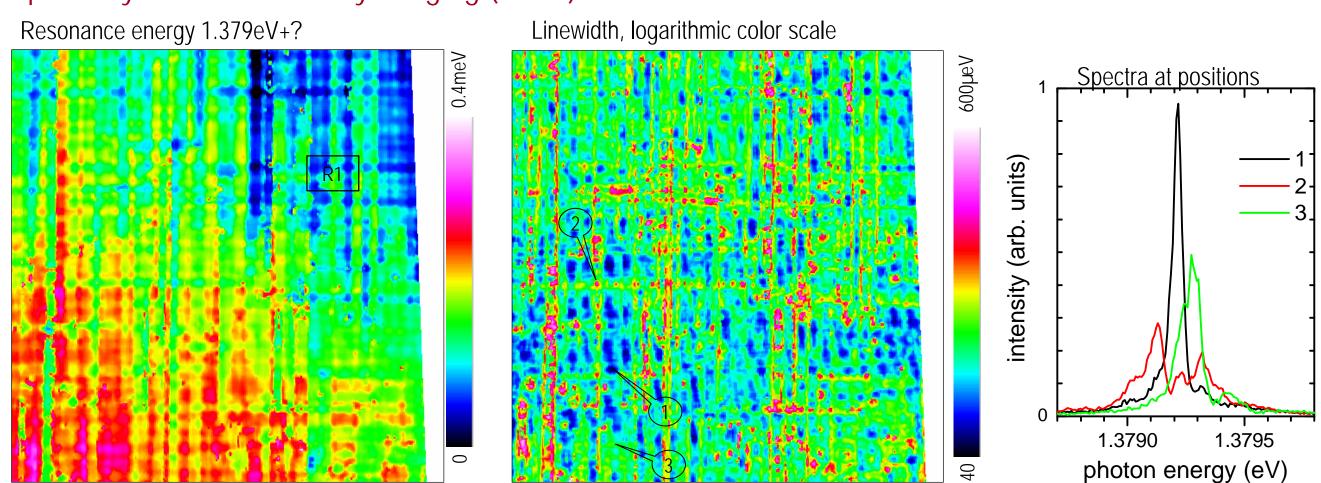


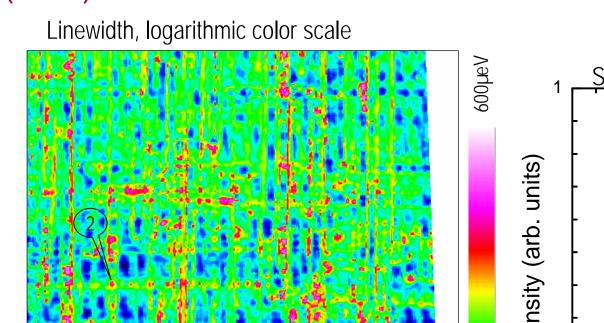
 $\lambda_0 = 900$ nm, $\lambda = \lambda_0 / n = 257$ nm



• predicted cavity linewidth 90µeV for nominal refractive indices of GaAs 3.498 and AIAs 2.928 (at 900nm, 4K, J. Appl. Phys. 87, 7825) • Measured linewidth down to 45µeV • within 1% accuracy of the refractive indices, minimum predicted linewidth 42µeV: negligible effect of intrinsic absorption and scattering • Confirmed by Reitzenstein et al, Appl. Phys. Lett. 90, 251109 (2007): linewidth of 8µeV observed in >30 pair Bragg AIAs/GaAs micropillars

Spectrally resolved intensity imaging $(\rightarrow \rightarrow)$

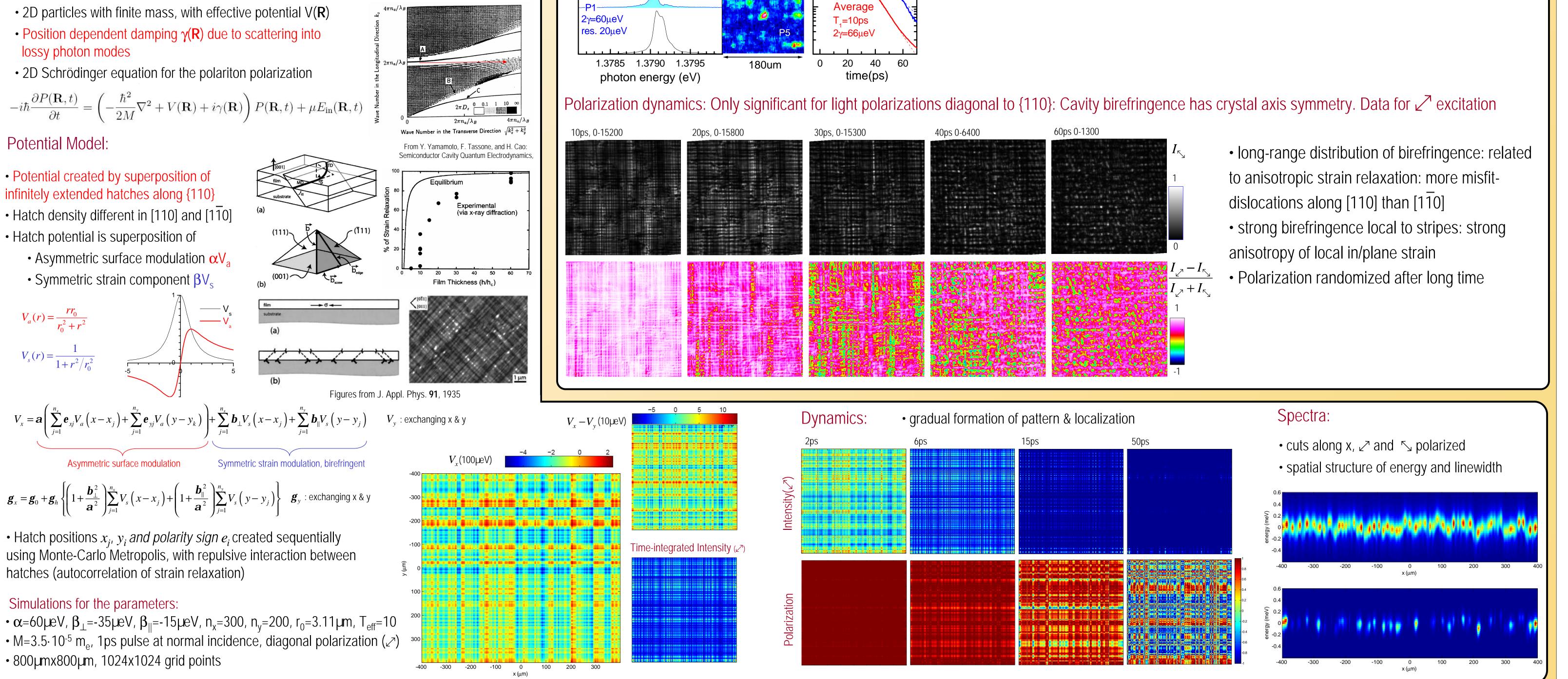




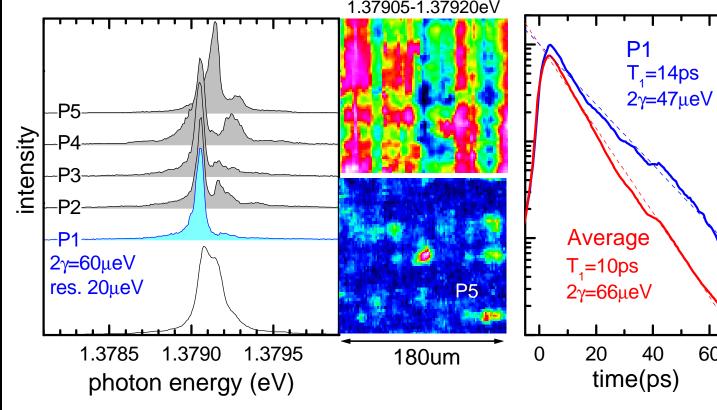
 spatially inhomogeneous distribution of resonance energy and width • small overall gradient of energy ~100µeV/mm due to thickness gradient (10-4/mm) • linewidths down to 45µeV, below nominal cavity linewidth (20µeV resolution)

Theoretical Model

• Polariton properties dominated by long-range in-plane disorder, created by misfit dislocation in the strained AIAs/GaAs system (0.14% lattice mismatch)



Analysis of long-lived polariton state



• Selected spot of long temporal decay shows extended average decay time • Local emission spectrum linewidth in agreement with increased decay time Spectra al all long-lived spots have narrorw linewidth • localized polariton states form in a local minimum of the energy landscape

